SEARCH REQUEST FORM

Scientifi	c and Technical Informati	ion Center	, ,
Requester's Full Name: P. Laue Art Unit: 2100 Phone Number:		#:73139 Date:	10/15/0
Mail Box and Bldg/Room Location:		rmat Preferred (circle): Paper	Diale' E mail
Wan Box and Bidg Room Location.	Keans Fo	mat Frederied (Circle). Faper	Disk E-mail
If more than one search is submitted,		in order of need.	******
Please provide a detailed statement of the search topic, species or structures, keywords, synonyms, acronyms, a terms that may have a special meaning. Give examples pertinent claims, and abstract.	and registry numbers, and combine w	vith the concept or utility of the inven	tion. Define any
Title of Invention:			
Inventors (please provide full names):			
Earliest Priority Filing Date:		N	
For Sequence Searches Only Please include all perta appropriate serial number.		sional, or issued patent numbers) alo	ng with the
Litique 5,	ation 910,181		10-15-01 P12:08 IN
STAFF USE ONLY Searcher: 4767 Searcher Phone: 6-4767 Searcher Location: 4640 Date Searcher Picked Up: 101501 Date Completed: 0 5 01 Searcher Prep & Review Time:	Type of search NA Sequence (#) AA Sequence (#) Structure (#) Bibliographic Litigation Full Text	Vendors and cost where some strain price of the strain price of th	********* applicable
Clerical Prep Time:	Patent Family	WWW/Internet	

Online Time:

Green, Shirelle

From:

Sent:

Laufer, Pinchus Monday, October 15, 2001 11:41 AM STIC-EIC2100

To:

Subject:

More litigation searches - CAN THESE BE PUT "NEXT"

Importance:

High

Here are 2 more; CAN THESE BE DONE BEFORE THE 3?

(1) 09/821,371 which is a Reissue of US Patent 5,890,128 Inventors: Benjamin Diaz and M. Inez Genera

(2) 09/871,978 which is a Reissue of US Patent 5,910,181 Inventors: Makoto Hatakenaka et al.

Thank You,

Pinchus

Pinchus M. Laufer, Ph.D. Special Programs Examiner, Technology Center 2100 Computer Architecture, Software, & Electronic Commerce US Patent and Trademark Office (703) 306-4160 plaufer@uspto.gov

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1 PN="US 5910181"
     S1
?t s1/9
1/9/1
DIALOG(R) File 345: Inpadoc/Fam. & Legal Stat
(c) 2001 EPO. All rts. reserv.
14683804
Basic Patent (No, Kind, Date): DE 19755707 Al 19981008 < No. of Patents: 004
PATENT FAMILY:
CHINA (CN)
 Patent (No, Kind, Date): CN 1195891 A 19981014
   SEMICONDUCTOR INTEGRATED CIRCUIT AND METHOD OF TESTING SYNCHRONOUS
     DYNAMIC RANDOM MEMORY CORE (English)
   Patent Assignee: MITSUBISHI ELECTRIC CORP (JP)
   Author (Inventor):
                         HATAKENAKA MAKOTO
                                              (JP);
                                                     YAMAZAKI AKIRA (JP);
     TOMISHIMA SHIGEKI (JP)
                            JP 9786600 A
                                            19970404
   Priority (No, Kind, Date):
   Applic (No, Kind, Date): CN 97125547 A
                                            19971212
   IPC: * H01L-027/108; G01R-031/3183
   Derwent WPI Acc No: * G 98-533087
   Language of Document: Chinese
GERMANY (DE)
 Patent (No, Kind, Date): DE 19755707 Al 19981008
   INTEGRIERTE HALBLEITERSCHALTUNG MIT IN EINEM EINZELCHIP INTEGRIERTEN
     SYNCHRONEN DRAM-KERN UND LOGIK-SCHALTKREIS SOWIE VERFAHREN ZUM
     PRUEFEN DES SYNCHRONEN DRAM-KERNS Single semiconductor chip with
     SDRAM core and integrated logic circuit (German)
   Patent Assignee: MITSUBISHI ELECTRIC CORP (JP)
   Author (Inventor): HATAKENAKA MAKOTO (JP); TOMISHIMA SHIGEKI (JP);
     YAMAZAKI AKIRA (JP); YAMAGATA TADATO (JP)
   Priority (No, Kind, Date): JP 9786600 A
                                            19970404
   Applic (No, Kind, Date): DE 19755707 A
                                            19971215
   IPC: * G11C-011/407
   Derwent WPI Acc No: * G 98-533087; G 98-533087
   Language of Document: German
GERMANY (DE)
 Legal Status (No, Type, Date, Code, Text):
                      19970404 DE AA
   DE 19755707
                                              PRIORITY (PATENT
                  P
                             APPLICATION) (PRIORITAET (PATENTANMELDUNG))
                             JP 9786600 A 19970404
   DE 19755707
                       19971215 DE AE
                                              DOMESTIC APPLICATION (PATENT
                             APPLICATION) (INLANDSANMELDUNG
                              (PATENTANMELDUNG))
                             DE 19755707 A
                                              19971215
   DE 19755707
                       19981008
                                 DE A1
                                              LAYING OPEN FOR PUBLIC
                             INSPECTION (OFFENLEGUNG)
                   Ρ
                       19981008 DE OP8
   DE 19755707
                                              REQUEST FOR EXAMINATION AS
                             TO PARAGRAPH 44 PATENT LAW (PRUEFUNGSANTRAG
                             GEM. PAR. 44 PATG. IST GESTELLT)
JAPAN (JP)
 Patent (No, Kind, Date): JP 10283777 A2 19981023
   SEMICONDUCTOR INTEGRATED CIRCUIT WHERE SDRAM CORE AND LOGIC CIRCUIT ARE
     MIXEDLY MOUNTED ON SINGLE CHIP AND TESTING METHOD OF THE SDRAM CORE
      (English)
   Patent Assignee: MITSUBISHI ELECTRIC CORP
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Author (Inventor): HATANAKA MAKOTO; YAMAZAKI AKIRA; TOMISHIMA SHIGEKI; YAMAGATA NARIHITO Priority (No, Kind, Date): JP 9786600 A 19970404 Applic (No, Kind, Date): JP 9786600 A 19970404 IPC: * G11C-011/407; G11C-011/401; G11C-029/00 Derwent WPI Acc No: * G 98-533087 Language of Document: Japanese UNITED STATES OF AMERICA (US) Patent (No, Kind, Date): US 5910181 A 19990608 SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE COMPRISING SYNCHRONOUS DRAM CORE AND LOGIC CIRCUIT INTEGRATED INTO A SINGLE CHIP AND METHOD OF TESTING THE SYNCHRONOUS DRAM CORE (English) Patent Assignee: MITSUBISHI ELECTRIC CORP (JP) Author (Inventor): HATAKENAKA MAKOTO (JP); YAMAZAKI AKIRA (JP); TOMISHIMA SHIGEKI (JP); YAMAGATA TADATO (JP) Priority (No, Kind, Date): JP 9786600 A 19970404 Applic (No, Kind, Date): US 964236 A 19971104 National Class: * 714718000 IPC: * G06F-011/00 Derwent WPI Acc No: * G 98-533087 Language of Document: English UNITED STATES OF AMERICA (US) Legal Status (No, Type, Date, Code, Text): 19970404 US AA US 5910181 Ρ PRIORITY (PATENT) JP 9786600 A 19970404 19971104 US AE US 5910181 APPLICATION DATA (PATENT) Ρ (APPL. DATA (PATENT)) US 964236 A 19971104 US 5910181 Р 19971104 US AS02 ASSIGNMENT OF ASSIGNOR'S INTEREST MITSUBISHI DENKI KABUSHIKI KAISHA 2-3, MARUNOUCHI 2-CHOME, CHIYODA-KU TOKYO 100, ; HATAKENAKA, MAKOTO: 19971020; YAMAZAKI, AKIRA: 19971020; TOMISHIMA, SHIGEKI: 19971027; YAMAGATA, TADATO: 19971020

US 5910181

Ρ

19990608 US A

PATENT

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Litigations - 5910181 - P. Laufer
?us5910181/pn
 Term not in index/PN-CRXX: US5910181
  Term not in index/PN-LITA: US5910181
  Term not in index/PN-PAST : US5910181
 LGST
                             1
 CRXX
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 LITA
                             0
 PAST
  ** SS
          2 : Results
                              1
 Search statement
?prt ss2 max 1
 1/1 LGST (1/1) - (C) LEGSTAT
PN - US 5910181 [US5910181]
 AP - US 964236/97 19971104 [1997US-0964236]
 DT - US-P
 ACT - 19971104 US/AE-A
        APPLICATION DATA (PATENT)
        {US 964236/97 19971104 [1997US-0964236]}
      - 19971104 US/AS02
        ASSIGNMENT OF ASSIGNOR'S INTEREST
        MITSUBISHI DENKI KABUSHIKI KAISHA 2-3, MARUNOUCHI 2-CHOME, CHIYODA-KU
        TOKYO 100, * HATAKENAKA, MAKOTO : 19971020; YAMAZAKI, AKIRA :
        19971020; TOMISHIMA, SHIGEKI : 19971027; YAMAGATA, TADATO : 19971020
      - 19990608 US/A
        PATENT
 UP - 2000-06
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LEVEL 1 OF 1 PATENT 5,910,181

<=2> GET 1st DRAWING SHEET OF 15

Jun. 8, 1999

Semiconductor integrated circuit device comprising synchronous DRAM core and logic circuit integrated into a single chip and method of testing the synchronous DRAM core

CORE TERMS: pin, external, input, semiconductor, integrated, control signals, synchronous, dynamic, clock, random access memory...

LEXIS-NEXIS
Library: PATENT
File: ALL

5,910,181 OR 5910181

Your search request has found no CASES.

To edit the above request, use the arrow keys. Be sure to move the cursor to the end of the request before you enter it.

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5,910,181 OR 5910181

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5,910,181 OR 5910181

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Library: PATENT
File: JNLS